

**Notice of References Cited**Application/Control No.  
10/020,304Applicant(s)/Patent Under  
Reexamination  
RAVINDRA ET ALExaminer  
A. SeferArt Unit  
2826

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,767,557	06-1998	Kizilyalli	257/403
	B	US-6,066,880	05-2000	Kusunoki	257/379
	C	US-6,222,234	04-2001	Imai	257/347
	D	US-5,998,828	12-1999	Oeno et al	257/315
	E	US-4,302,764	11-1981	Fang et al	357/23
	F	US-6,462,379	10-2002	Higashi et al	257/347
	G	US-6,373,102	04-2002	Huang	257/345
	H	US-5,208,473	05-1993	Komori et al	257/345
	I	US-6,221,703	04-2001	Liu et al	437/174
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 9-321276	12-1997	Japan	Tashiro et al	
	O	JP 2-280381	11-1990	Japan	Takahasi et al	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.